SCDS028E – JULY 1995 – REVISED APRIL 1997

- **5-Ω Switch Connection Between Two Ports**
- **TTL-Compatible Input and Output Levels**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages**

## description

The SN74CBT16211 provides 24 bits of high-speed TTL-compatible bus switching. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

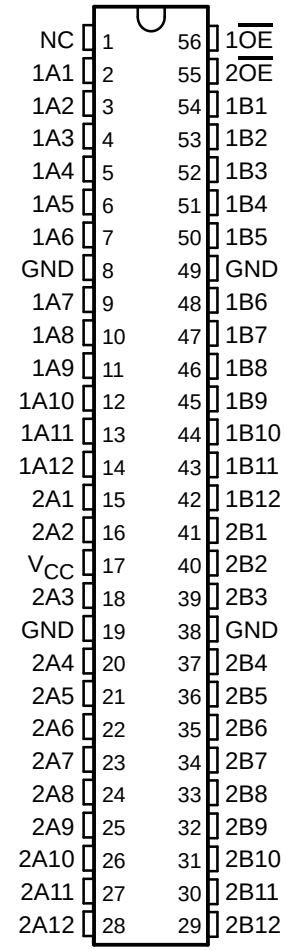
The device operates as a 12-bit or 24-bit bus switch. When $1\overline{OE}$ is low, 1A is connected to 1B. When $2\overline{OE}$ is low, 2A is connected to 2B.

The SN74CBT16211 is characterized for operation from –40°C to 85°C.

**FUNCTION TABLE**

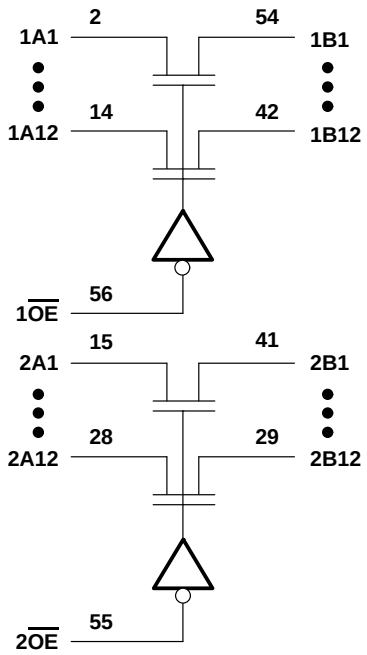
| INPUTS | | INPUTS/OUTPUTS | |
|---|---|---|---|
| $1\overline{OE}$ | $2\overline{OE}$ | 1A, 1B | 2A, 2B |
| L | L | 1A = 1B | 2A = 2B |
| L | H | 1A = 1B | Z |
| H | L | Z | 2A = 2B |
| H | H | Z | Z |

**DGG, DGV, OR DL PACKAGE**
**(TOP VIEW)**




NC – No internal connection

## logic diagram (positive logic)




## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, $V_{CC}$ . . . . . –0.5 V to 7 V
Input voltage range, $V_I$ (see Note 1) . . . . . –0.5 V to 7 V
Continuous channel current . . . . . 128 mA
Input clamp current, $I_{IK}$ ($V_I < 0$) . . . . . –50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2): DGG package . . . . . 81°C/W
DGV package . . . . . 86°C/W
DL package . . . . . 74°C/W
Storage temperature range, $T_{stg}$ . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

## recommended operating conditions

| | | MIN | MAX | UNIT |
|---|---|---|---|---|
| $V_{CC}$ | Supply voltage | 4 | 5.5 | V |
| $V_{IH}$ | High-level control input voltage | 2 | | V |
| $V_{IL}$ | Low-level control input voltage | | 0.8 | V |
| $T_A$ | Operating free-air temperature | –40 | 85 | °C |

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | | MIN | TYP† | MAX | UNIT |
|---|---|---|---|---|---|---|---|---|
| $V_{IK}$ | | $V_{CC}$ = 4.5 V, | $I_I$ = –18 mA | | | | –1.2 | V |
| $I_I$ | | $V_{CC}$ = 0 V, | $V_I$ = 5.5 V | | | | 10 | μA |
| | | $V_{CC}$ = 5.5 V, | $V_I$ = 5.5 V or GND | | | | ±1 | |
| $I_{CC}$ | | $V_{CC}$ = 5.5 V, | $I_O$ = 0, | $V_I$ = $V_{CC}$ or GND | | | 3 | μA |
| $\Delta I_{CC}$‡ | Control pins | $V_{CC}$ = 5.5 V, | One input at 3.4 V, | Other inputs at $V_{CC}$ or GND | | | 2.5 | mA |
| $C_i$ | Control pins | $V_I$ = 3 V or 0 | | | | 4.5 | | pF |
| $C_{io(OFF)}$ | | $V_O$ = 3 V or 0, | $\overline{OE}$ = $V_{CC}$ | | | 5.5 | | pF |
| $r_{on}$§ | | $V_{CC}$ = 4 V, | $V_I$ = 2.4 V, | $I_I$ = 15 mA | | 14 | 20 | Ω |
| | | $V_{CC}$ = 4.5 V | $V_I$ = 0 | $I_I$ = 64 mA | | 5 | 7 | |
| | | | | $I_I$ = 30 mA | | 5 | 7 | |
| | | | $V_I$ = 2.4 V, | $I_I$ = 15 mA | | 8 | 12 | |

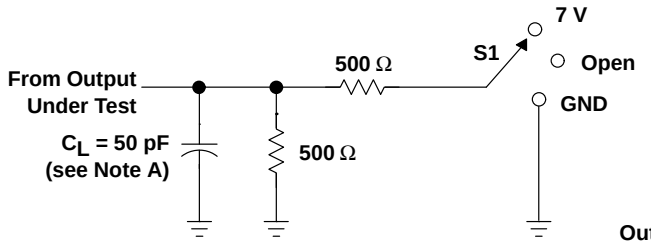
† All typical values are at $V_{CC}$ = 5 V, $T_A$ = 25°C.
‡ This is the increase in supply current for each input that is at the specified TTL voltage level rather than $V_{CC}$ or GND.
§ Measured by the voltage drop between the A and B terminals at the indicated current through the switch. On-state resistance is determined by the lowest voltage of the two (A or B) terminals.

## switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $V_{CC}$ = 5 V ± 0.5 V | | $V_{CC}$ = 4 V | | UNIT |
|---|---|---|---|---|---|---|---|
| | | | MIN | MAX | MIN | MAX | |
| $t_{pd}$¶ | A or B | B or A | | 0.25 | | 0.25 | ns |
| $t_{en}$ | $\overline{OE}$ | A or B | 3.9 | 9.3 | | 10.1 | ns |
| $t_{dis}$ | $\overline{OE}$ | A or B | 3.3 | 8.5 | | 7.1 | ns |

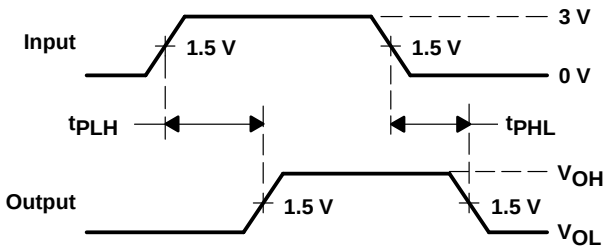
¶ This parameter is warranted but not production tested. The propagation delay is based on the RC time constant of the typical on-state resistance of the switch and a load capacitance of 50 pF, when driven by an ideal voltage source (zero output impedance).

## PARAMETER MEASUREMENT INFORMATION

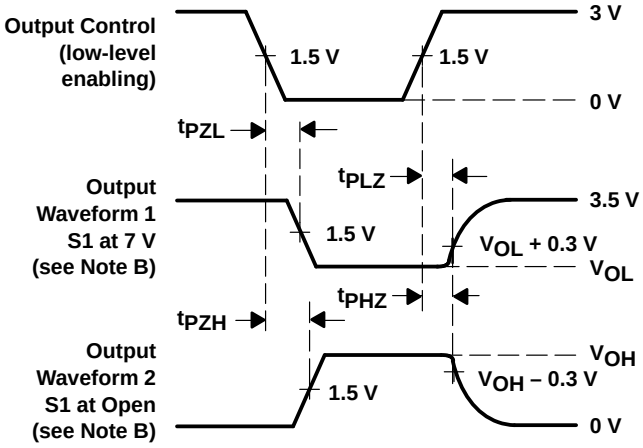



LOAD CIRCUIT

| TEST | S1 |
|---|---|
| $t_{pd}$ | Open |
| $t_{PLZ}/t_{PZL}$ | 7 V |
| $t_{PHZ}/t_{PZH}$ | Open |




VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES




VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTES: A. $C_L$ includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O$ = 50 Ω, $t_r$ ≤ 2.5 ns, $t_f$ ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. $t_{PLZ}$ and $t_{PHZ}$ are the same as $t_{dis}$.
F. $t_{PZL}$ and $t_{PZH}$ are the same as $t_{en}$.
G. $t_{PLH}$ and $t_{PHL}$ are the same as $t_{pd}$.

**Figure 1. Load Circuit and Voltage Waveforms**

## IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.